



# Dynamic Range



Parts of readout chain have gain control:

- ◆ APV:  $\pm 20$  in 5 steps%
- ◆ Laser Driver: 4 steps of  $\pm ?$

But this is to compensate intrinsic variations in performance.

(Residual variations still  $\pm 20\%$ ).

⇒ Gain of readout chain effectively constant.



# Dynamic Range



FED has two data taking modes:

Low trigger rates -

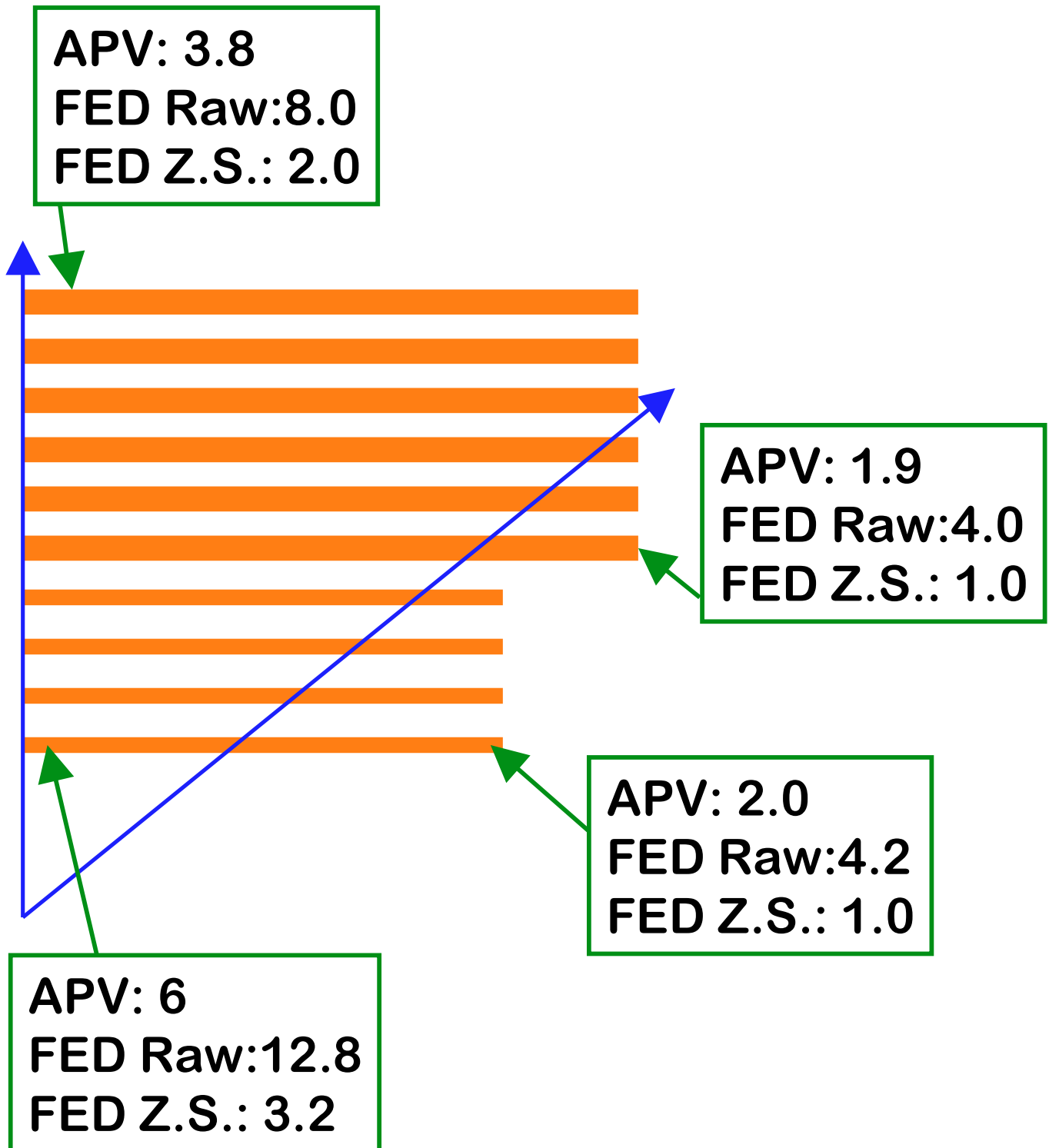
Raw Data: 10 bit ADC

High trigger rates -

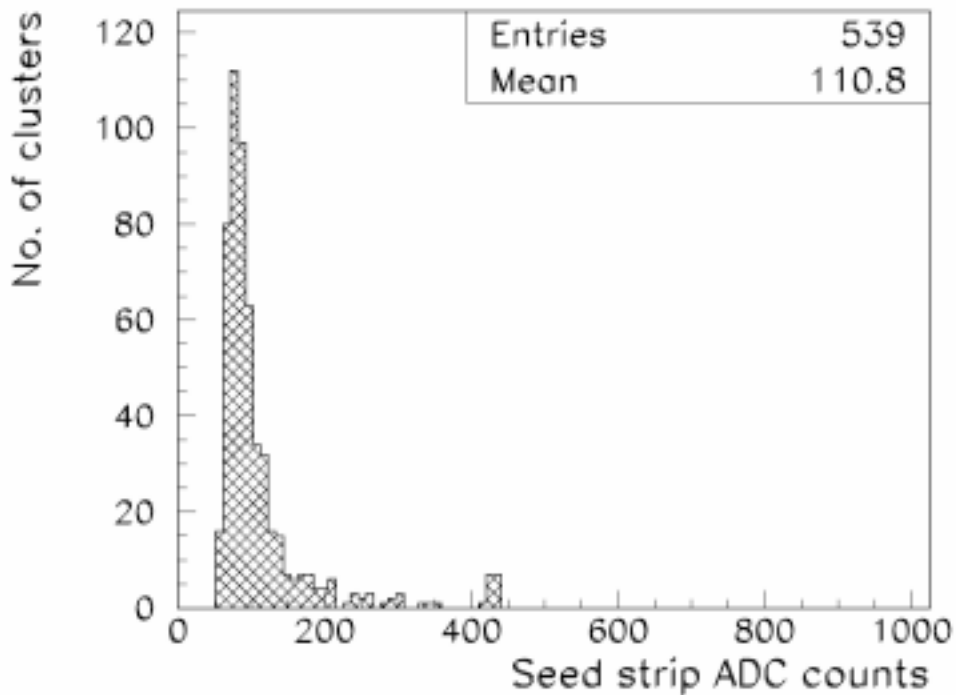
Zero Suppressed:

After pedestal + CM subtraction:  
drops 2 MSBs  $\Rightarrow$  8 bits left.

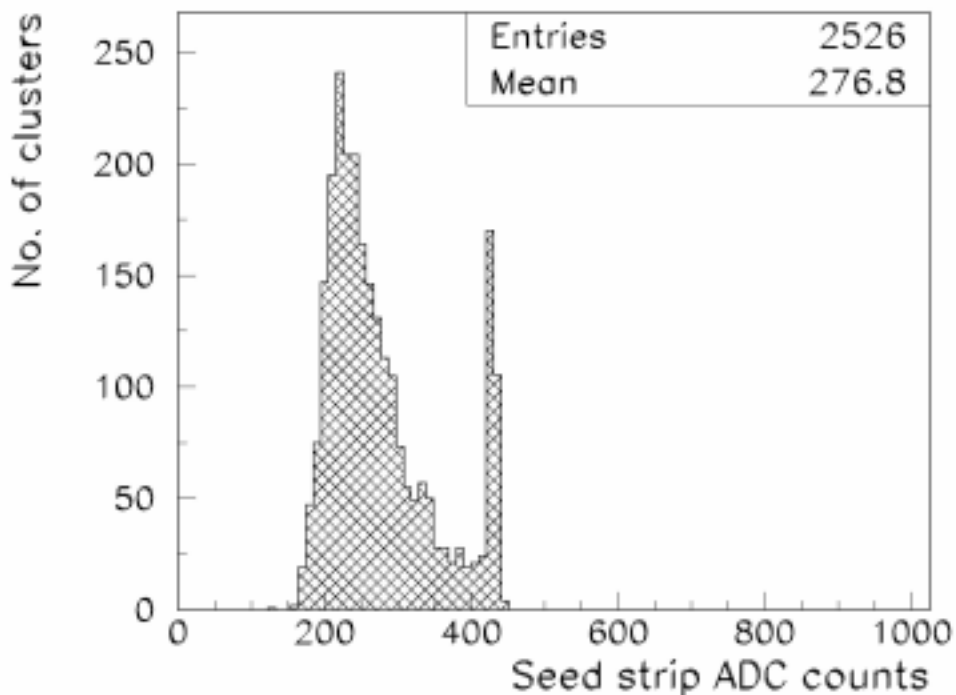
## Dynamic ranges (in MIPs) in barrel



## High Pt track, 10 bit readout

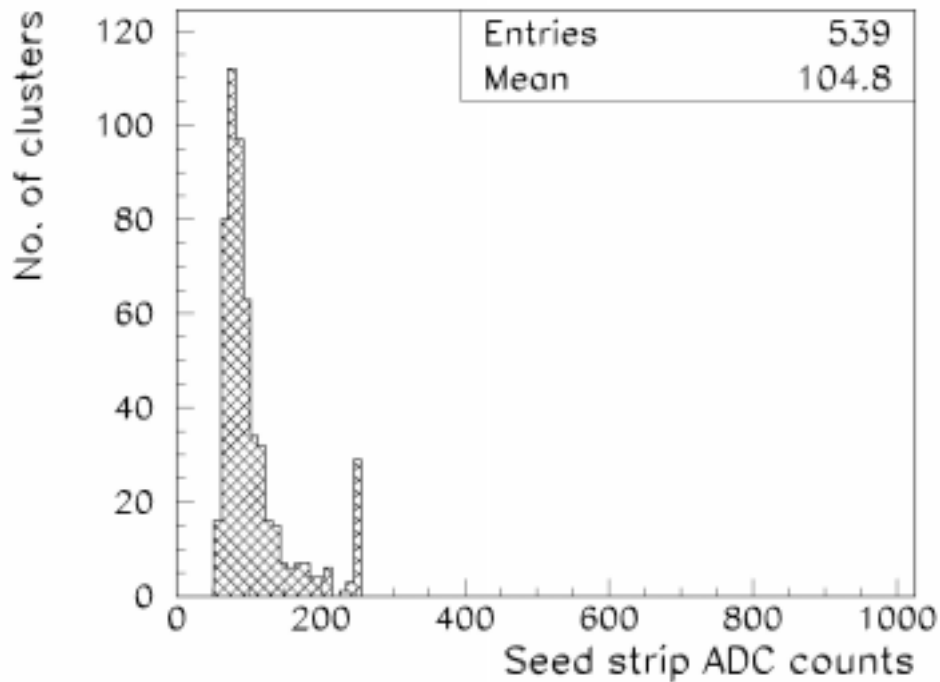


## 1st wafer in rod of inner layer

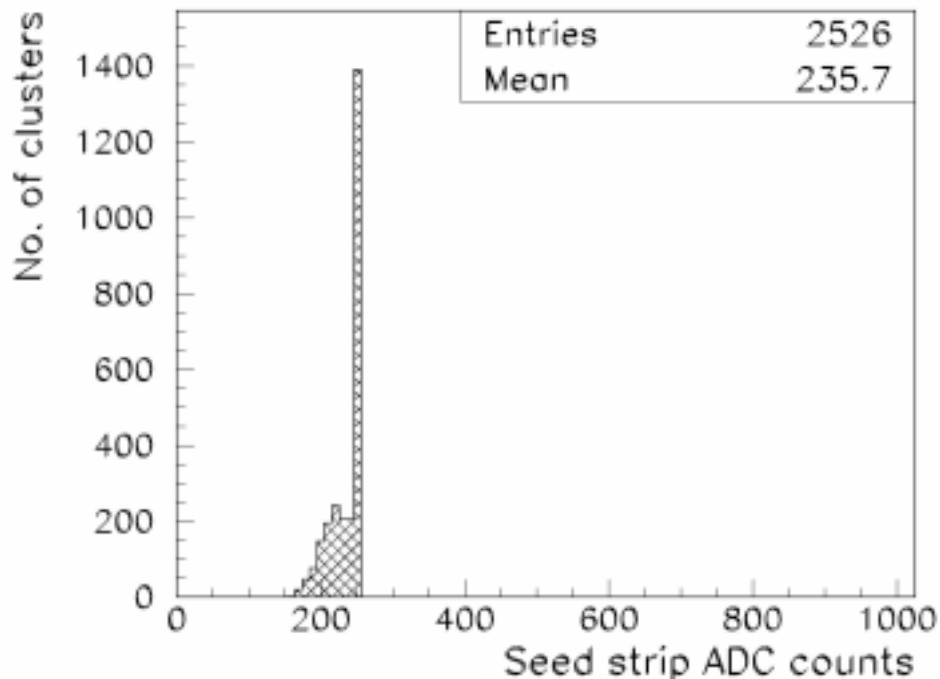


## 6th wafer in rod of inner layer

## High Pt track, 8 bit readout

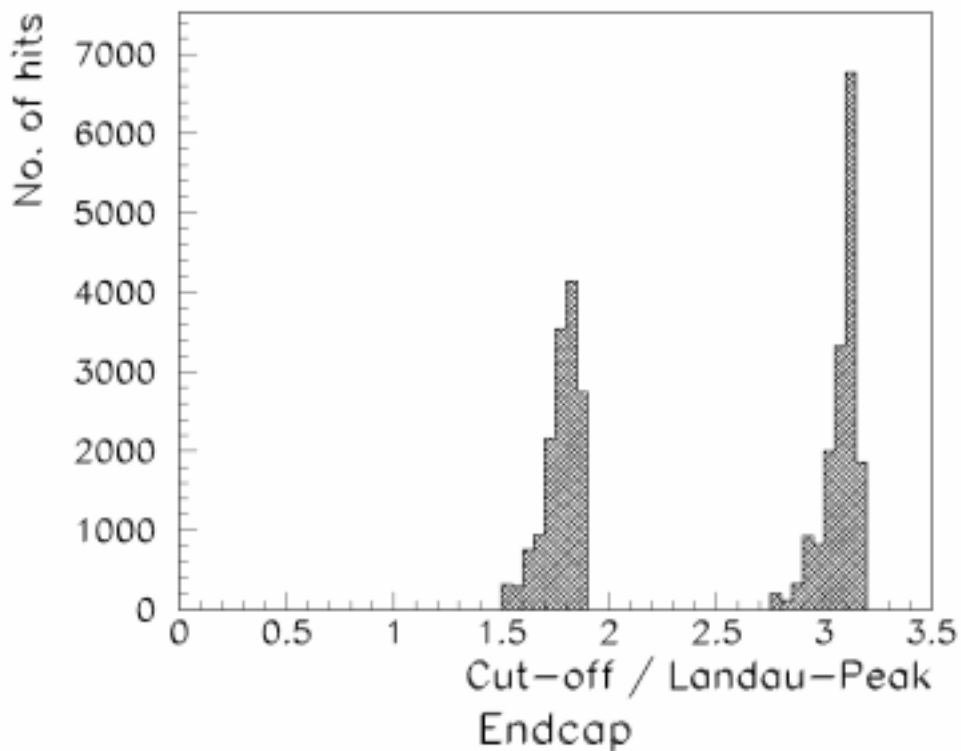
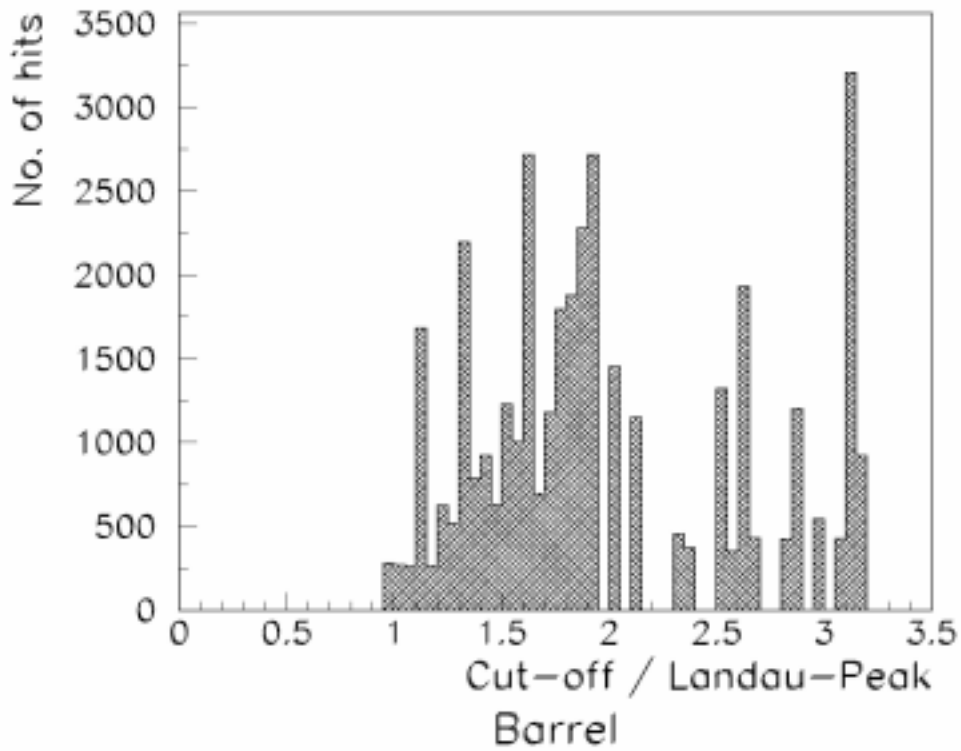


## 1st wafer in rod of inner layer



## 6th wafer in rod of inner layer

MB events:  $P_t > 1 \text{ GeV}/c$





# Dynamic Range



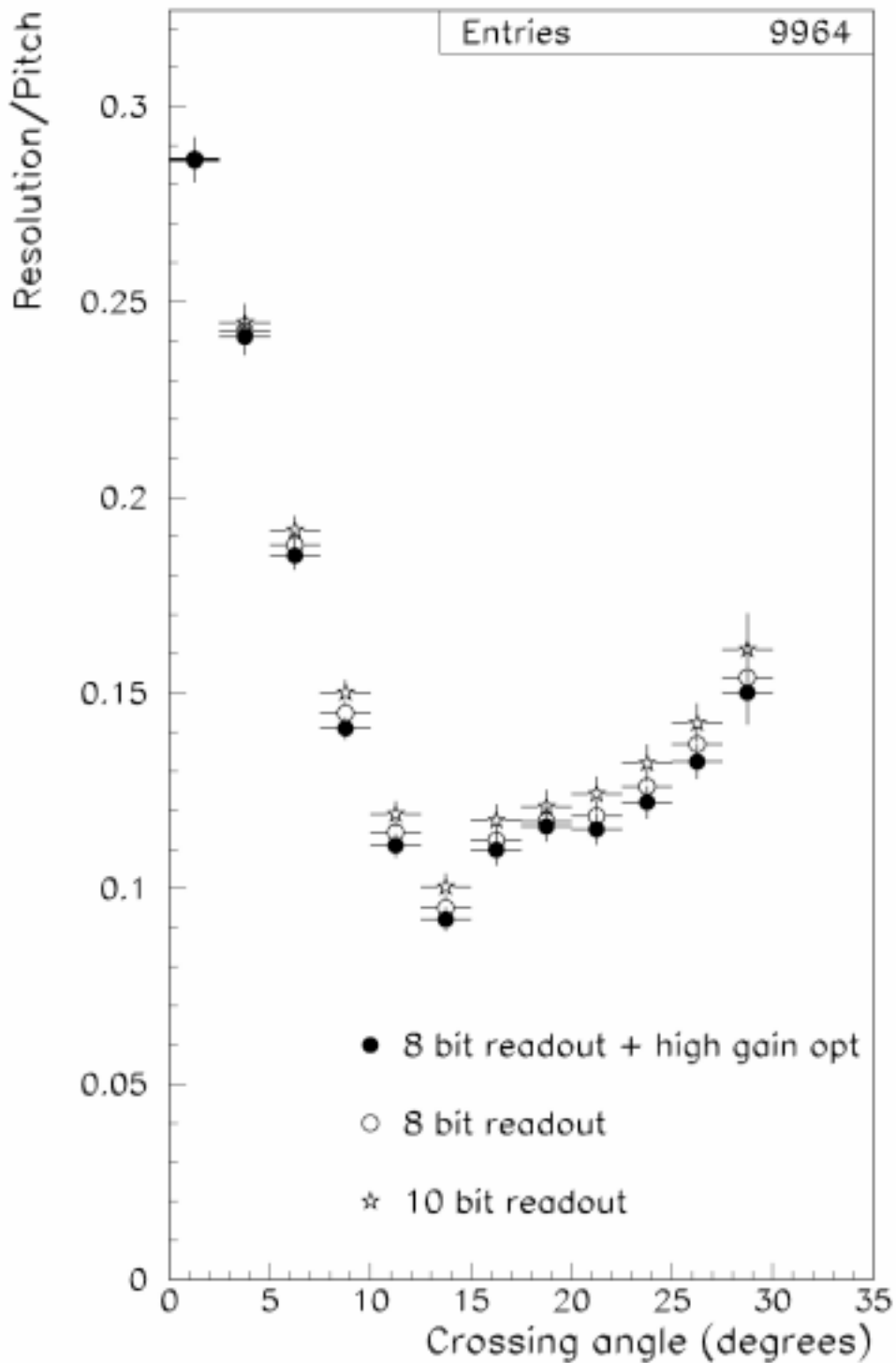
In normal data taking, Landau badly truncated in some parts of detector.  
Do we care ?

- Must measure signal size for:
  - ◆ Calibration of gain differences.
  - ◆ Tuning Monte Carlo
  - ◆ Tracker synchronization with tracks.
  - ◆ Monitoring detector depletion ?
  - ◆  $dE/dx$  ?

Could this be done in calibrations runs ?

- Does truncation degrade position resolution ? Apparently not ...

6th wafer in rod of inner layer







# Dynamic Range



## Possible Solution (proposed F. Vasey)

### Standard:

Raw Data: 10 bits

Zero Suppressed: Drop 2 MSBs  $\Rightarrow$  8 bits

### New:

Zero Suppressed with gain 0.5:

Drop 1 MSB and 1 LSB  $\Rightarrow$  8 bits